

STUDENT NEWSLETTER

Students at Work



The lab has been very busy this month with students coming in to use the equipment for their research. **Ryan Shintani** (*top left*), a WM Applied Science graduate student, used the hardness tester to examine polymer/graphene oxide nano composites. **Thomas Dushatinski** (*below*), a CNU chemistry undergrad, uses our Atomic Force Microscope (AFM) to view carbon nanotubes on a glass substrate. **Kaitlyn Fields** (*bottom left*), a WM physics undergrad, uses the Hitachi 4700



Scanning Electron Microscope to view contamination on test samples from the new JLab clean room.



High School Tour

On Thursday, July 11th, 2013, Elizabeth City High School students visited the Applied Research Center. The students were given demonstrations on both the Phenom Scanning Electron Microscope (SEM) and the Hirox Optical Light Microscope. They were also given descriptions about what the other machines do and how they work.



Nick Moore explaining to students how the Hirox works.

Nick Arcand demonstrating the Hirox to the students.



The students watched and listened as each piece of equipment was described.

